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Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

		Applica	tion No.	Applicant(s)		
Office Action Summary		10/531	,553	NESTERENKO ET AL.		
		Examin	er	Art Unit		
		JARRE ¹	TT J. STARK	2823		
 Period for	The MAILING DATE of this commun	nication appears on t	he cover sheet with th	e correspondence a	ddress	
A SHOI WHICH - Extensic after SI - If NO pe - Failure Any rep	RTENED STATUTORY PERIOD F EVER IS LONGER, FROM THE M ons of time may be available under the provisions (6) MONTHS from the mailing date of this come period for reply is specified above, the maximum s to reply within the set or extended period for reply by received by the Office later than three months patent term adjustment. See 37 CFR 1.704(b).	MAILING DATE OF sof 37 CFR 1.136(a). In no munication. tatutory period will apply and will, by statute, cause the a	THIS COMMUNICAT event, however, may a reply be will expire SIX (6) MONTHS f application to become ABANDO	ON. e timely filed rom the mailing date of this of the content o		
Status						
2a)⊠ T 3)□ S	esponsive to communication(s) filential his action is FINAL . ince this application is in condition losed in accordance with the pract	2b)☐ This action is for allowance exce	non-final. pt for formal matters,	-	e merits is	
Dispositio	n of Claims					
4a 5)□ C 6)⊠ C 7)□ C	laim(s) 1-20 is/are pending in the a) Of the above claim(s) is/a laim(s) is/a laim(s) is/are allowed. laim(s) 1-20 is/are rejected. laim(s) is/are objected to. laim(s) are subject to restri	are withdrawn from o				
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10)□ Tr A R	ne specification is objected to by the drawing(s) filed on is/are pplicant may not request that any objected the oath or declaration is objected to	: a) ☐ accepted or ection to the drawing(sg the correction is requ) be held in abeyance. uired if the drawing(s) is	See 37 CFR 1.85(a). objected to. See 37 C		
Priority un	der 35 U.S.C. § 119					
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 						
2) Notice of 3) Informa) of References Cited (PTO-892) of Draftsperson's Patent Drawing Review (I tion Disclosure Statement(s) (PTO/SB/08) lo(s)/Mail Date	PTO-948)	4) Interview Summ Paper No(s)/Mai 5) Notice of Inform 6) Other:			

DETAILED ACTION

Response to Arguments

Applicant's arguments directed to the newly amended claims filed 1/28/2009 have been fully considered but they are not persuasive.

Applicants argue that the Examiner's prima facie case for obviousness fails because the Examiner erroneously concluded that it would have been obvious to replace the thermal compression bonding disclosed in Bhat et al, with the isostatic thermal compression bonding disclosed in Cohn et al.

This argument is traversed in view of the following rationale:

Bhat et al. discloses a the method of thermal compression bonding semiconductor wafers comprising the steps of first bringing together cleaned wafers creating a weak bond within a chamber and then further bonding the wafer though means of applying heat and pressure. As in Applicant's invention, the purpose of invention is to thermally bond semiconductor wafers.

Bhat et al. is silent upon the use of *isostatic* pressure when applying the required pressure during thermal compression bonding, as required by the independent claims.

For such a teaching, the Examiner relies on <u>Cohn et al.</u>, which discloses <u>isostatic</u> pressure is a functional equivalent alternative for applying the necessary pressure for thermal compression bonding. <u>Coh et al.</u> states:

"Still another alternative for supplying the necessary pressure and heat is to place a <u>substrate</u> <u>pair</u> into a high-temperature bag (made of a material such as polyimide or metal foil) and subject <u>it to hot -isostatic-pressing</u>."

The foregoing means of applying pressure for thermal compression boning includes Bhat et al 's means of applying pressure by pressing the two wafers together for the thermal compression bonding (Bhat et al. col. 2, Ln 28-48) in addition to alternative of applying isostatic pressure, which satisfies the claim language.

The Examiner's position is that it would have been within the scope of one of ordinary skill in the art at the time of the invention to combine the teachings of Bhat and Cohn to enable the pressure step of Bhat to be performed according to the teachings of Cohn because one of ordinary skill would have been motivated to look to alternative suitable methods of performing the disclosed pressure step of Bhat and art recognized suitability for an intended purpose has been recognized to be motivation to combine. MPEP § 2144.07.

Replacing <u>Bhat et al.'s</u> means for applying compressive pressure with <u>Cohn et al.</u>'s alternative means for applying the compressive pressure would have been prima facie obvious.

The artisan would have been motivated to find a way to create stronger and/or more efficient bonds when using <u>Bhat et al.'s</u> method, which employs compression by pressing. See Dystar, 464 F.3d at 1368 (an implicit motivation to combine exists when the "improvement" is technology-independent and the combination of references results

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in a product or process that is "stronger, cheaper, cleaner, faster, lighter, smaller, more durable, or more efficient.") (emphasis added).

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Cohn et al. teaches the functional equivalence of compression by pressing and compression by isostatic pressure, which satisfies the claim language. The fact that Cohn et al. compressing means includes the compression means used by Bhat et al. to perform the same type of bonding, also might be capable of bonding Bhat et al. semiconductor wafers. Furthermore, the total number of means for applying pressure disclosed by Bracken constitutes "a finite number of identified, predictable solutions," as is required to demonstrate obviousness using an "obvious to try" rationale. KSR, 127 S. Ct. at 1742. We therefore find that the artisan would have been motivated to try Cohn et al.'s means for applying compressive pressure, including the isostatic pressure, in order to determine whether any of them yields a reduction in the bonding time and/or a increase in strength and efficiency of the bond. See KSR, 127 S. Ct. at 1742 ("When there is a design need or market pressure to solve a problem and there are a finite number of identified, predictable solutions, a person of ordinary skill has good reason to pursue the known options within his or her technical grasp."). The claimed invention therefore would have been prima facie obvious over Bhat et al. in view of Cohn et al

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Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 1-20 are rejected under 35 U.S.C. 103(a) as being unpatentable over Bhat et al. (US 5,207,864) in view of Cohn et al. (US 7,276,789 B1).

Regarding claim 1, 11, 12, 14-16, 19, Bhat et al. discloses a method for semiconductor wafer bonding, the method comprising steps of:

providing semiconductor wafers to be bonded (Bhat, Abstract);

cleaning the wafers to remove particle and chemical contaminants from bonding surfaces of the wafers (Bhat, Abstract);

bringing the bonding surfaces of the wafers together to weakly bond the wafers to each other (Bhat, Abstract);

placing the wafers in a pressurization chamber (Bhat, Abstract);

applying bonding pressure to the wafers (Bhat, Abstract);

heating the wafers during said step of applying bonding pressure (Bhat,

Abstract); and

controlling and maintaining said steps of heating and applying bonding pressure for a period of time to substantially strengthen bonding between the wafers (Bhat, Abstract);

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Bhat et al. does not specify that the pressure is applied solely through isostatic pressure. It was however known to those of ordinary skill in the art to solely apply an isostatic type of pressure when bonding wafers. At the time of the invention it was conventional use hot press bonding as well as Hot Isostatic Press or Hot Isostatic Processing (HIP) diffusion bonding. HIP is known conventional means of applying evenly controlled pressure. It would be obvious to one of ordinary skill in the art to select isostatic means for applying pressure when bonding wafers. For an examples of one of ordinary skill in the art applying isostatic pressure when performing a diffusion bonding process see Cohn et al. (entire document).

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"Still another alternative for supplying the necessary pressure and heat is to place a <u>substrate</u> <u>pair</u> into a high-temperature bag (made of a material such as polyimide or metal foil) and subject <u>it to hot -isostatic-pressing</u>."

It would have been within the scope of one of ordinary skill in the art at the time of the invention to combine the teachings of <u>Bhat</u> and <u>Cohn</u> to enable the pressure step of <u>Bhat</u> to be performed according to the teachings of <u>Cohn</u> because one of ordinary skill would have been motivated to look to alternative suitable methods of performing the disclosed pressure step of <u>Bhat</u> and art recognized suitability for an intended purpose has been recognized to be motivation to combine. MPEP § 2144.07.

When there is a design need or market pressure to solve a problem and there are a finite number of identified, predictable solutions, a person of ordinary skill in the art has good reason to pursue the known options within his or her technical grasp. If this

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leads to the anticipated success, it is likely the product not of innovation but of ordinary skill and common sense. KSR Int'l Co v. Teleflex Inc.

Regarding claim 2, Bhat_in view of <u>Cohn_disclose</u> the method of claim 1, further comprising steps of: cooling the wafers; and removing the wafers from the pressurization chamber (<u>Bhat</u>, Col. 6 line 10).

Regarding claim 3, Bhat_in view of <u>Cohn</u> disclose the method of claim 2, wherein said step of cooling is conducted while said step of controlling and maintaining continues said step of applying bonding pressure, followed by a step of depressurization (Bhat, Abstract).

Regarding claim 4, Bhat_in view of <u>Cohn</u> disclose the method of claim 1, wherein said step of controlling and maintaining comprises: creating a temperature ramp and a pressure ramp to substantially strengthen bonding between the wafers (<u>Bhat</u>, Entire document—the process disclosed by <u>Bhat</u> is to improve bonding which implicitly mean to strengthen bonding);

Regarding claim 5, Bhat_in view of <u>Cohn</u> disclose the method of claim 4, wherein said step of controlling and maintaining creates the temperature ramp as a function that is independent from the pressure ramp (<u>Bhat</u>, Abstract).

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Regarding claim 6, Bhat_in view of <u>Cohn</u> disclose the method of claim 1, wherein said step of heating commences prior to said step of applying pressure (<u>Bhat</u>, Abstract).

Regarding claim 7, Bhat_in view of <u>Cohn</u> disclose the method of claim 1, wherein said step of heating commences with or after said step of applying pressure (<u>Bhat</u>, Abstract).

Regarding claim 8, Bhat_in view of <u>Benavides_and/or Curbishley_disclose</u> the method of claim 1, wherein said step of cleaning creates hydrogen terminated surfaces at the bonding surfaces (Inherent result of HF dip).

Regarding claim 9, Bhat_in view of <u>Cohn</u> disclose the method of claim 1, wherein said step of bringing creates one of a Van der Waals and Hydrogen bond (<u>Bhat</u>, Abstract).

Regarding claims 10 and 13, Bhat in view of Cohn disclose the method of claim 9, wherein said step of bringing brings the bonding surfaces into direct contact with each other with or without an intervening layer (direct and indirect bonding are known in that art. The selection of the two types of bonding, indirect or direct bonding, is a matter of design choice which is dependent upon the materials which are being

bonded. One of ordinary skill in the art would be able to select one of the two known process on the base of its suitability

Regarding claim 17, Bhat in view of Cohn disclose the method of claim 1, wherein said steps of providing, cleaning and bringing are repeated to form a plurality of weakly bonded pairs of wafers and said steps of applying, heating, and controlling and maintaining are carried out with the plurality of weakly bonded pairs of wafers simultaneously in the pressurization chamber (Bhat, Abstract).

Regarding claim 18, <u>Bhat</u> in view of <u>Cohn</u> disclose the method of claim 1, further comprising, prior to said step of placing, loading said wafers in an unsealed container, and wherein said step of placing is carried out by placing said unsealed container in said pressurization chamber (<u>Bhat</u>, Abstract).

Regarding claim 20, Bhat_in view of <u>Cohn</u> disclose the method of claim 19, further comprising a step of controlling said heating and pressing to induce strain in at least one of said wafers (inherent result of heat/pressure bonding process).

Conclusion

Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP

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§ 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to JARRETT J. STARK whose telephone number is (571)272-6005. The examiner can normally be reached on Monday - Thursday 7:00AM - 5:30PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Matthew Smith can be reached on (571) 272-1907. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

/Michelle Estrada/ Primary Examiner, Art Unit 2823

2/27/2008 /J. J. S./ Examiner, Art Unit 2823